

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Mechanical and climatic test methods –
Part 7: Internal moisture content measurement and the analysis of other residual
gases**

**Dispositifs à semiconducteurs – Méthodes essais mécaniques et climatiques –
Partie 7: Mesure de la teneur en humidité interne et analyse des autres gaz
résiduels**



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CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references	5
3 Terms and definitions	5
4 Test apparatus	5
4.1 Mass spectrometer method	5
4.2 Mass spectrometer	5
4.2.1 Spectra range.....	5
4.2.2 Detection limit	6
4.2.3 System calibration	6
4.2.4 Calibration for other gases	6
4.2.5 Daily calibration check.....	7
4.2.6 Substitution	7
4.2.7 Precision tuning.....	7
4.2.8 Record keeping	7
4.3 Vacuum opening chamber	7
4.4 Piercing arrangement	7
4.5 Pressure-sensing device	7
5 Procedure	8
6 Failure criteria	9
7 Implementation.....	9
8 Summary.....	10
Bibliography.....	11

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MECHANICAL AND CLIMATIC TEST METHODS –****Part 7: Internal moisture content measurement
and the analysis of other residual gases**

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International Standard IEC 60749-7 has been prepared by IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2002 and constitutes a technical revision. This second edition has been completely re-written so as to align it with the text of the latest versions of MIL-STD-750, method 1018 and MIL-STD-883, method 1018.

The main change is the removal of the two alternative methods formerly designated method 2 and method 3.

The text of this standard is based on the following documents:

FDIS	Report on voting
47/2087/FDIS	47/2098/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60749 series, under the general title *Semiconductor devices – Mechanical and climatic test methods*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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